

George Papaioannou

List of Publications by Year in descending order

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26
papers

306
citations

933447

10
h-index

888059

17
g-index

26
all docs

26
docs citations

26
times ranked

324
citing authors

#	ARTICLE	IF	CITATIONS
1	Effect of Ambient on the Field Emission Induced-Damage in Dielectric-Less MEMS Capacitive Structures. IEEE Transactions on Device and Materials Reliability, 2022, 22, 205-216.	2.0	1
2	On the Discharge Transport Mechanisms Through the Dielectric Film in MEMS Capacitive Switches. Journal of Microelectromechanical Systems, 2020, 29, 202-213.	2.5	10
3	Engineering of Porphyrin Molecules for Use as Effective Cathode Interfacial Modifiers in Organic Solar Cells of Enhanced Efficiency and Stability. ACS Applied Materials & Interfaces, 2018, 10, 20728-20739.	8.0	22
4	Functionalized Zinc Porphyrins with Various Peripheral Groups for Interfacial Electron Injection Barrier Control in Organic Light Emitting Diodes. ACS Omega, 2018, 3, 10008-10018.	3.5	11
5	Low Work Function Lacunary Polyoxometalates as Electron Transport Interlayers for Inverted Polymer Solar Cells of Improved Efficiency and Stability. ACS Applied Materials & Interfaces, 2017, 9, 22773-22787.	8.0	23
6	Dielectric Charging Asymmetry in SiN Films Used in RF MEMS Capacitive Switches. IEEE Transactions on Device and Materials Reliability, 2017, 17, 138-145.	2.0	8
7	Optimization of Dielectric Material Stoichiometry for High-Reliability Capacitive MEMS Switches. IEEE Microwave and Wireless Components Letters, 2016, 26, 174-176.	3.2	10
8	A simple constitutive model for dielectric charging based on Frenkel-Poole mechanism. , 2015, , .		0
9	Conductive reliability modelling of capacitive MEMS. , 2015, , .		0
10	Modelling of the dynamical behaviour of floating electrode MEMS. , 2015, , .		1
11	A MIM capacitor study of dielectric charging for RF MEMS capacitive switches. Facta Universitatis - Series Electronics and Energetics, 2015, 28, 113-122.	0.9	5
12	Reliability assessment of electrostatically driven MEMS devices: based on a pulse-induced charging technique. Journal of Micromechanics and Microengineering, 2012, 22, 045016.	2.6	2
13	Charge collection mechanism in MEMS capacitive switches. , 2012, , .		13
14	Nanotribology-based novel characterization techniques for the dielectric charging failure mechanism in electrostatically actuated NEMS/MEMS devices using force-distance curve measurements. Journal of Colloid and Interface Science, 2012, 365, 236-253.	9.4	11
15	Investigation of silicon nitride charging. Microelectronic Engineering, 2012, 90, 145-148.	2.4	22
16	Dielectric Charging in Capacitive RF MEMS Switches: The Effect of Extended Durations of Electric Stress. IEEE Microwave and Wireless Components Letters, 2011, 21, 592-594.	3.2	4
17	On the reliability of electrostatic NEMS/MEMS devices: Review of present knowledge on the dielectric charging and stiction failure mechanisms and novel characterization methodologies. Microelectronics Reliability, 2011, 51, 1810-1818.	1.7	54
18	The Impact of Dielectric Material and Temperature on Dielectric Charging in RF MEMS Capacitive Switches. NATO Science for Peace and Security Series B: Physics and Biophysics, 2010, , 141-153.	0.3	8

#	ARTICLE	IF	CITATIONS
19	A correlation of capacitive RF-MEMS reliability to AlN dielectric film spontaneous polarization. International Journal of Microwave and Wireless Technologies, 2009, 1, 43-47.	1.9	12
20	Bandpass filter modeling employing Lorentzian distribution. Microwave and Optical Technology Letters, 2009, 51, 1167-1169.	1.4	2
21	Effect of deposition conditions on charging processes in SiNx: Application to RF-MEMS capacitive switches. Microelectronic Engineering, 2009, 86, 404-407.	2.4	45
22	Dependence of dielectric charging on film thickness and deposition conditions. , 2008, , .		4
23	RF-MEMS Dielectric Charging: Dependence on Dielectric Film Polarization Procedures. , 2007, , .		1
24	Dielectric Discharging processes in RF-MEMS Capacitive Switches. , 2007, , .		9
25	Low-temperature properties and phototransport in silicon-oxide-insulator films synthesized by oxygen implantation. Journal of Applied Physics, 1988, 63, 4575-4579.	2.5	17
26	Physics of Charging in Dielectrics and Reliability of Capacitive RF-MEMS Switches. , 0, , .		11